Special Issue

Advances in Pattern Analysis for Identity Recognition and Verification II

Message from the Guest Editor

This Special Issue aims to summarize the recent advances in extracting and analyzing patterns that are able to identify the owner of them. Topics may include but are not limited to:

- Face recognition/verification;
- Iris recognition/verification;
- Fingerprint recognition/verification;
- Ear recognition/verification;
- Vein recognition/verification;
- Gait recognition/verification;
- EEG recognition/verification;
- Behavioral biometrics;
- Multimodal and adaptive biometric systems;
- Adversarial machine learning for biometric systems;
- Feature extraction;
- Storing and processing big biometric data;
- New biometric systems architectures;
- New benchmark datasets;
- New applications.

Guest Editor

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Deadline for manuscript submissions

closed (20 September 2022)

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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